

Introduction to Electron Microscopy

1. Orientation of the course
2. Freeze-fracture

9:10 - 9:20 KS Lu, Orientation
 9:20 - 10:20 SM Wang, Buffer & rotary shadowing
 10:30 - 11:20 KS Lu, Introduction to EM, Freeze-fracture
 11:20-12:10 CL Chien, Fixation & perfusion

Reference:

Bozzola J.J. and Russel L.D. (1999) ***Electron microscopy Principles and Techniques for Biologists.***

Second edition, Jones and Bartlett Publisher, Sudbury, Massachusetts, USA

2006-2-23

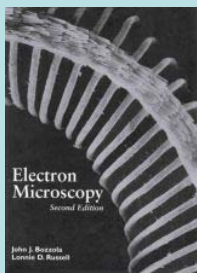
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Schedule for Hand-in Your Work

- 5/25 Reading micrograph
- 5/18 Photographic and Darkroom techniques
- 5/04 Electron microscope operation
- Specimens: **brain, kidney, liver**
- 5/04 Thick sections on slide (at least three sections stained with toluidine blue)
- 5/04 Thin sections on grids (at least two grids, stained with uranyl acetate & lead citrate)
- 5/25 Three EM pictures from your own specimens

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Electron Microscopy: Principles and Techniques for Biologists.

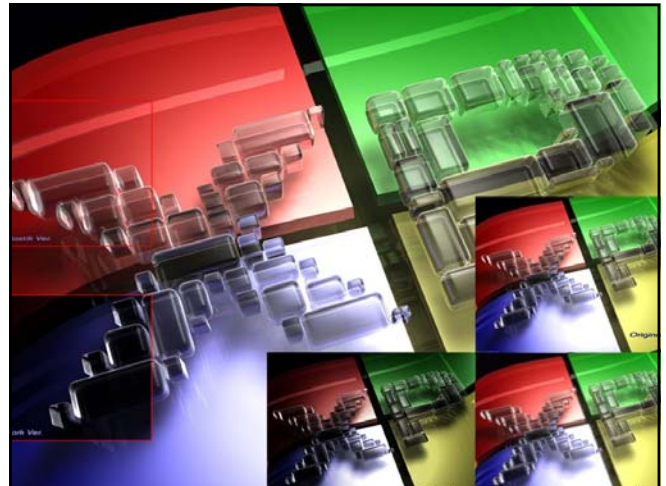
second edition, By John J. Bozzola and Lonnie D. Russell, 1999, Jones and Bartlett Publishers, Inc.



Rapid Freezing, Freeze Fracture and Deep Etching

(*Techniques in Modern Biomedical Microscopy 5*) By: Severs, Nicholas J.; Shotton, David M. 03/10/1995 John Wiley & Sons Inc

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Guidelines

- Technique-oriented, Practice-oriented
- **Safety (under supervision), Efficient, Work hard,**
- Take notes in every step,
- You must go through all the different procedures by yourself,
- Do all the work by your own,
- Hand in all the work on time

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Linear Equivalents

1	Angstrom = 0.1 nanometer (nm)
10	Angstroms = 1.0 nanometer [formerly millimicron (m μ)]
1000	nanometers = 1.0 micrometer (μ m) [formerly micron (μ)]
1000	micrometers = 1.0 millimeter (mm)
1000	millimeters = 1 meter (m)

1. Resolution (resolving power)

2. Numeral Aperture

3. Focal depth

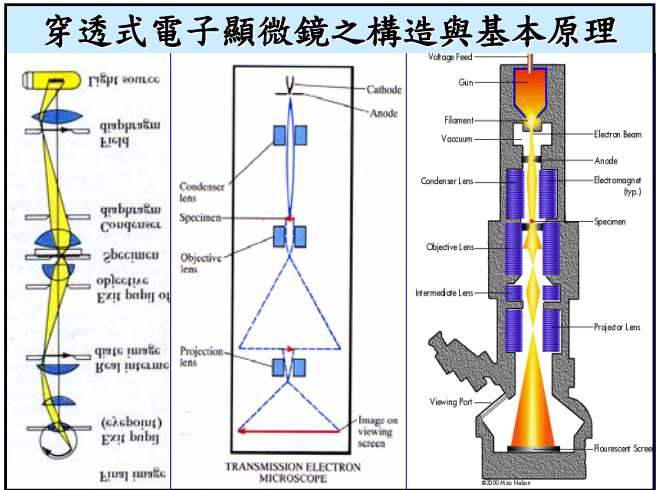
4. Field depth

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Resolution of eye versus instrument	
	Distance between Resolvable points
Human naked eyes	0.2 mm
Birght field microscope	0.2 μm
SEM	0.2 nm
TEM	0.2 nm
Theoretical	0.05 nm
Tissue section	1.0 nm

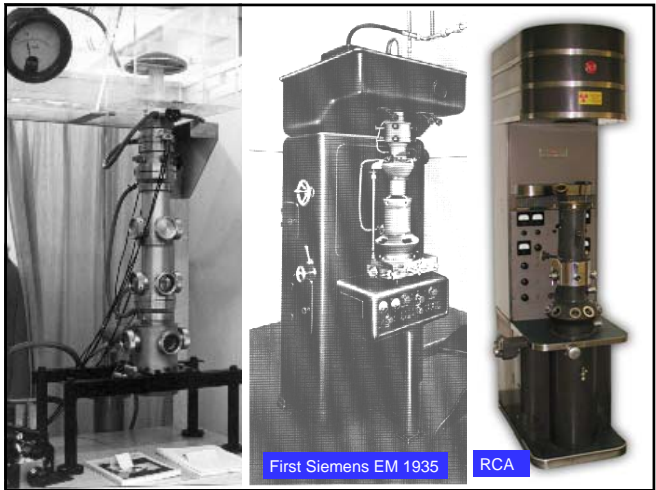
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解像力 (Resolution) Resolving power

$\alpha = 30^\circ$
NA 0.5
 d_0 660 nm

$d(\text{resolution}) = \frac{0.612 \lambda}{n \sin \alpha}$
 $n \sin \alpha = \text{NA (numerical aperture)}$



解像力 (Resolution) Resolving power

The ocular lens of microscope does not really affect the "resolution".

$\alpha = 14\frac{1}{2}^\circ$
NA 0.25
 d_0 1320 nm

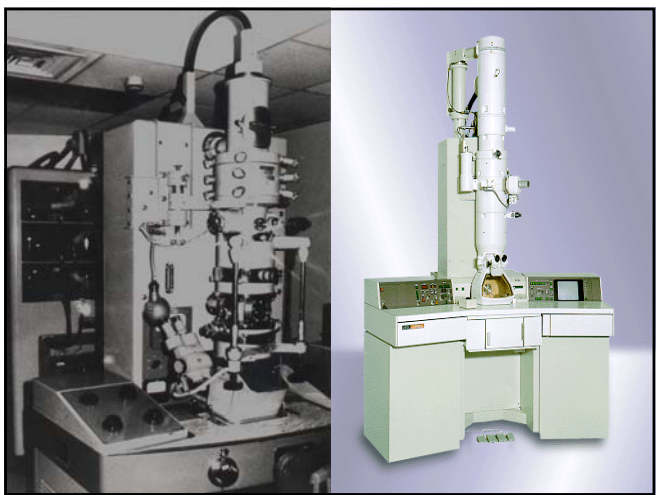
$\alpha = 30^\circ$
NA 0.5
 d_0 660 nm

$\alpha = 60^\circ$
NA 0.9 (air)
NA 1.3 (oil)
 d_0 air 370 nm
 d_0 oil 250 nm

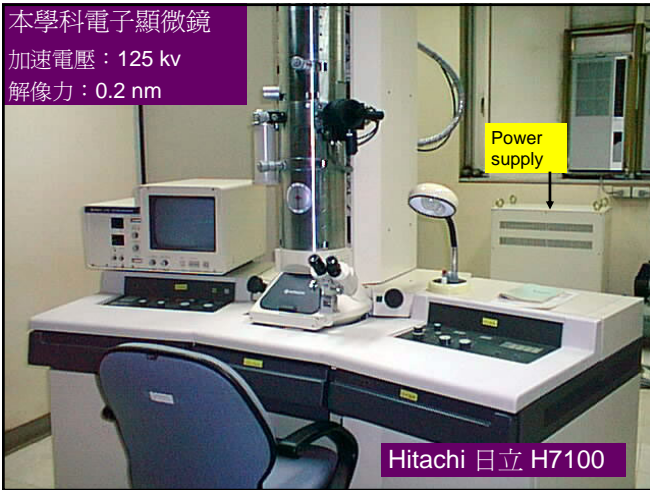
$d(\text{resolution}) = \frac{0.612 \lambda}{n \sin \alpha}$
 $n \sin \alpha = \text{NA (numerical aperture)}$

$n = 1.5, \sin 64^\circ = 0.9, \lambda = 380 \text{ nm (UV)}$
then $d = 0.172 \mu\text{m} \rightarrow 0.2 \mu\text{m}$

OLYMPUS PlanApo 60x/1.40 Oil Ph3

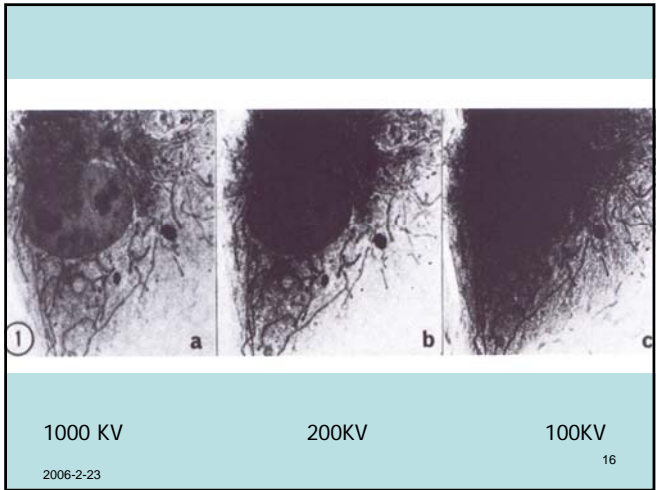


本學科電子顯微鏡
 加速電壓：125 kv
 解像力：0.2 nm



Hitachi 日立 H7100

Power supply



1000 KV

200KV

100KV

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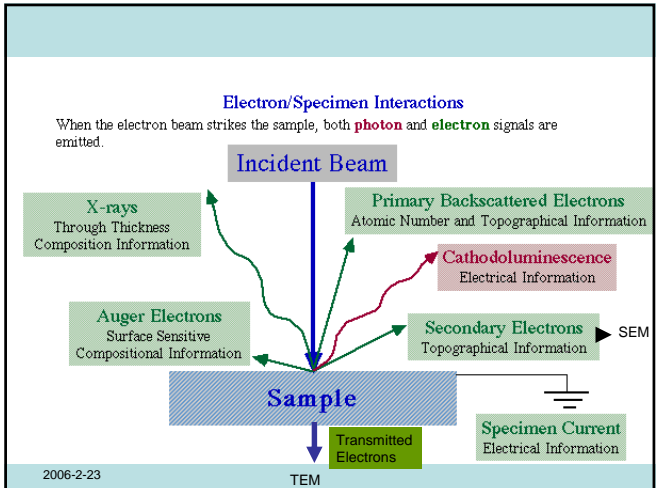
Ultra-High voltage
 Electron Microscope
 (1 MV, 1000KV)

 University of Colorado,
 Boulder, Colorado

超高压電子顯微鏡
 JSM-A RM1300/1000

- ◆ 点分解能：
 0.10nm (1,300kV)/
 0.13nm (1,000kV)
- ◆ 加速電圧：
 200~1,300kV
 (1,000kV)
- ◆ 倍率：×150~1,500,000

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Electron/Specimen Interactions
 When the electron beam strikes the sample, both photon and electron signals are emitted.

Incident Beam

X-rays
 Through Thickness
 Composition Information

Primary Backscattered Electrons
 Atomic Number and Topographical Information

Cathodoluminescence
 Electrical Information

Auger Electrons
 Surface Sensitive
 Compositional Information

Secondary Electrons
 Topographical Information

Sample

Transmitted Electrons
 TEM

Specimen Current
 Electrical Information

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3 MV Ultra-High Voltage Electron Microscope



Russia

CIT

Model: JE-3000 Height: 13.5 m Weight: 120 tons



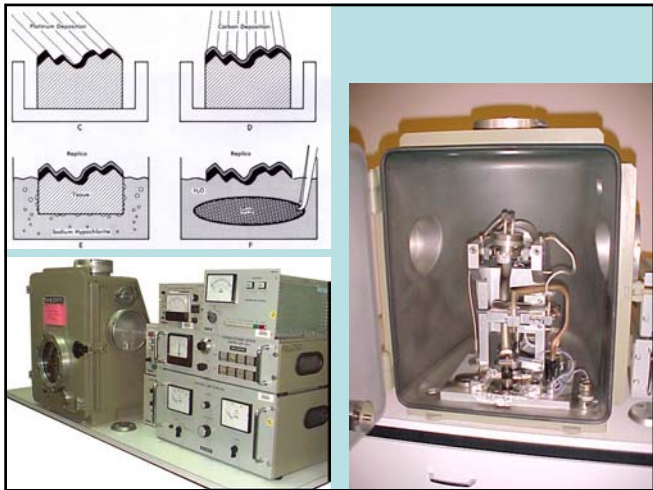
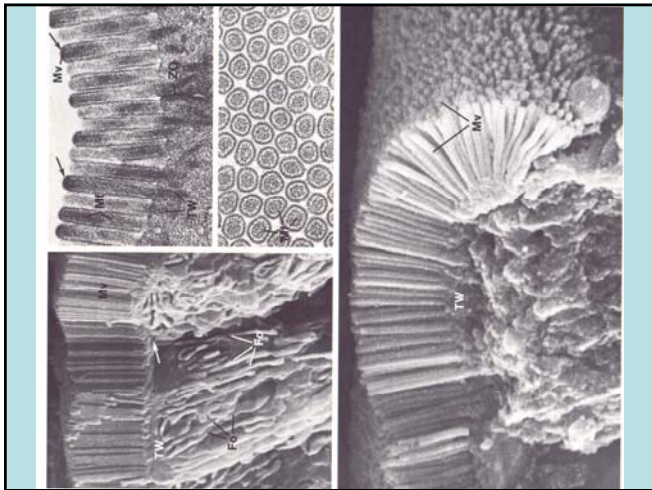
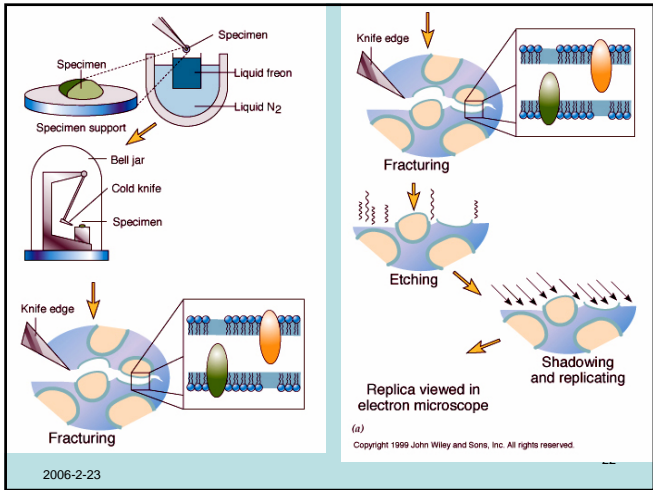
本學科電子顯微鏡：
 JSM-T330A (1989) 加速
 電壓：5-30 KV
 解像力：10 nm

- ◆分解能：0.6nm
- ◆加速電圧 0.5~30
- ◆倍率：×10~950,000
- ◆試料寸法 23mm(長さ) × 6mm(幅) × 3mm(高さ)
- ◆試料移動 X方向 24mm、Y方向8mm、Z方向0.6mm
- 傾斜±30°



Field Emission 走査電子顕微鏡
JSM-6000F

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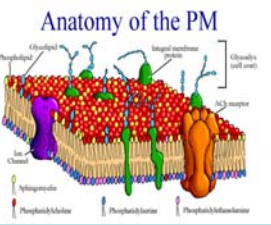
Freeze Fracture Technique

1. Fixation
2. Cryoprotection
3. Freezing
4. Freeze-fracturing
5. Shadowing
6. Cleaning (of replica)
7. TEM observation

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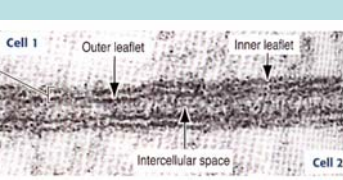
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Anatomy of the PM



The diagram shows the structure of the plasma membrane (PM) with various components labeled:

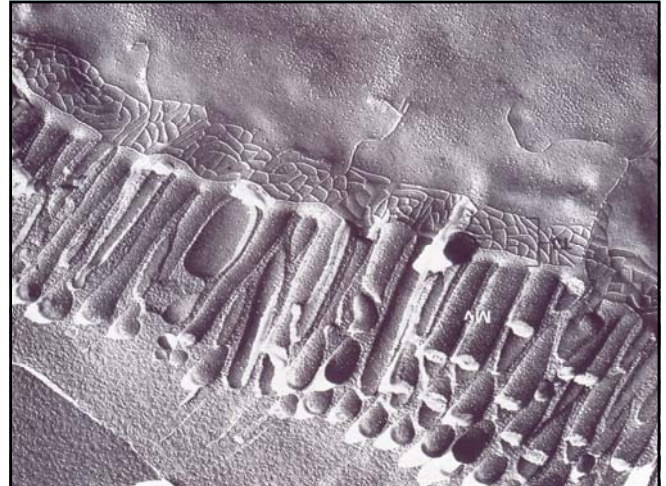
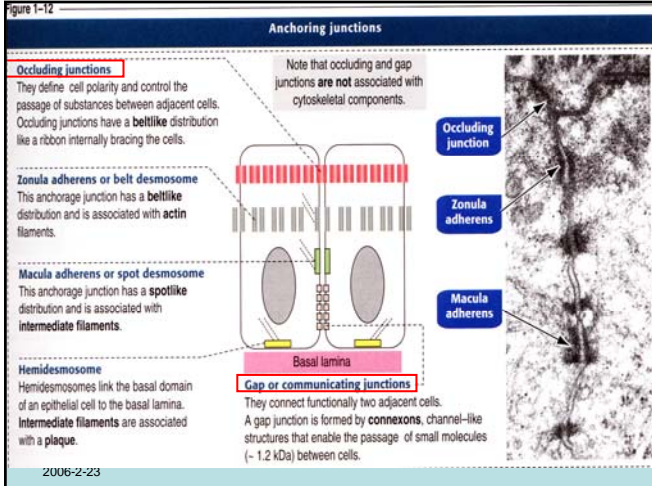
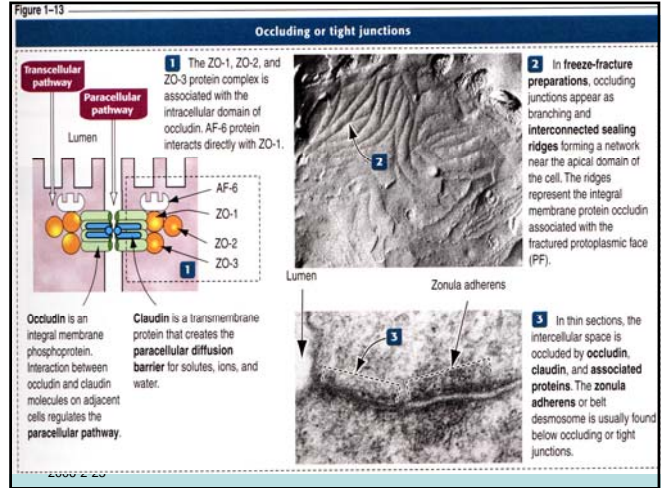
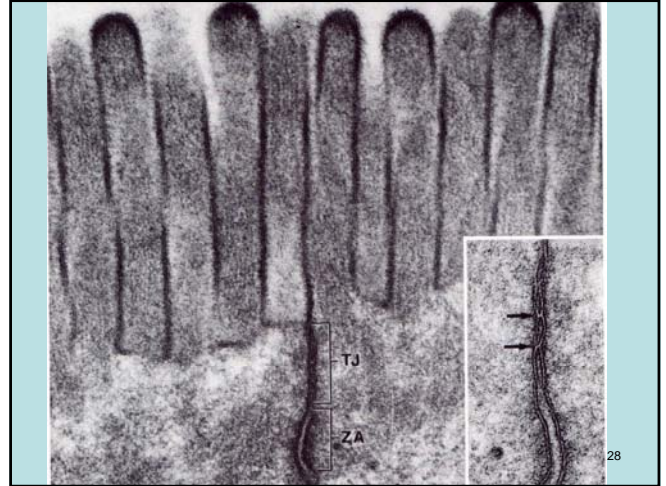
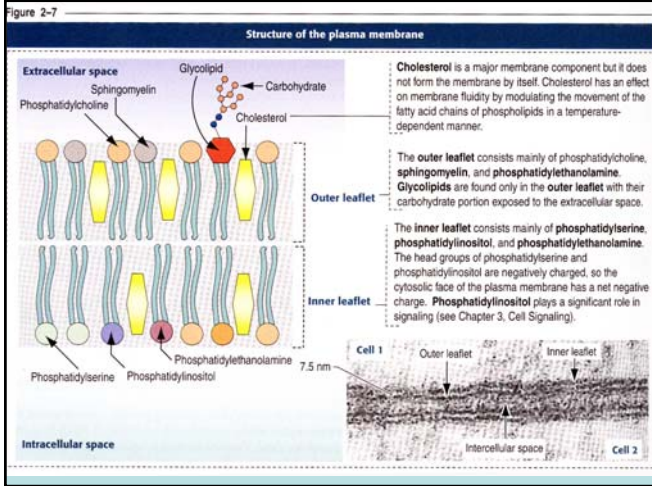
- Outer leaflet:** Contains phospholipids like phosphatidylcholine, sphingomyelin, and phosphatidylethanolamine.
- Inner leaflet:** Contains phospholipids like phosphatidylserine, phosphatidylinositol, and phosphatidylglycerol.
- Other components:** Glycolipids, integral membrane proteins, cholesterol, and carbohydrates.

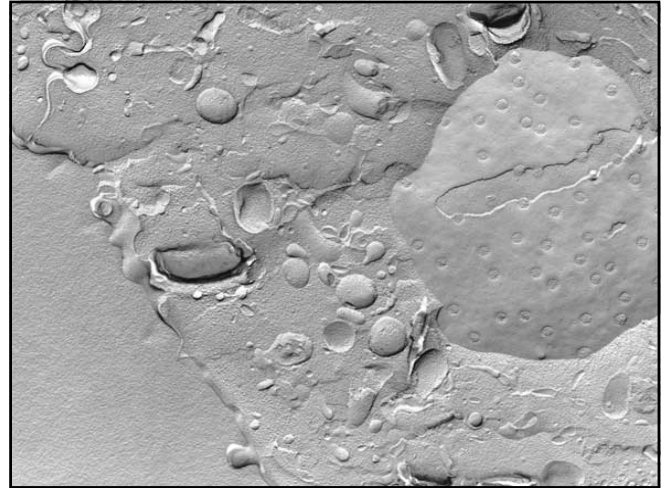
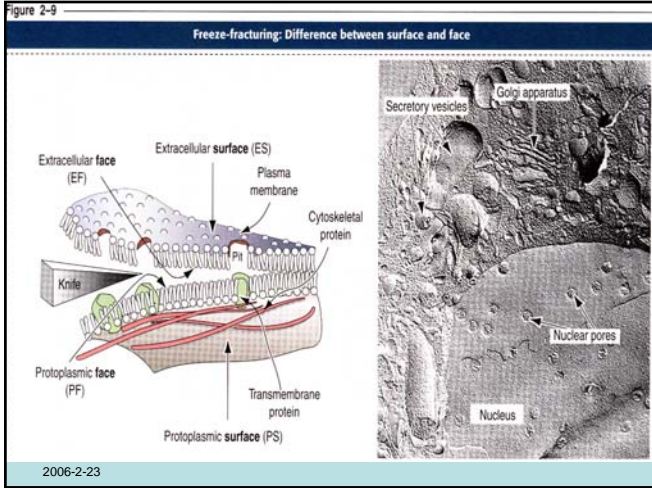
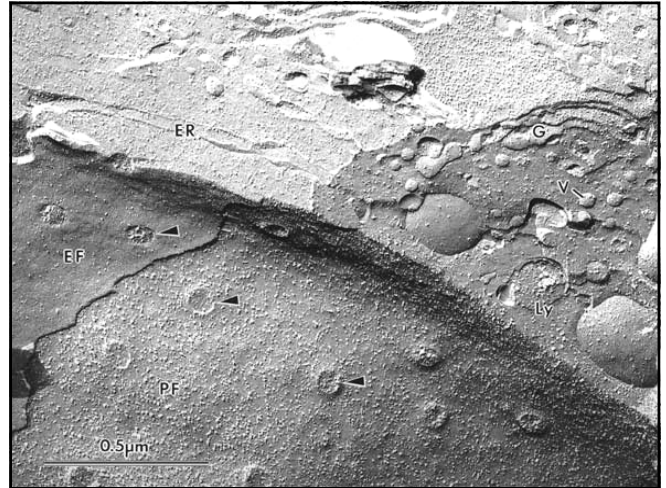
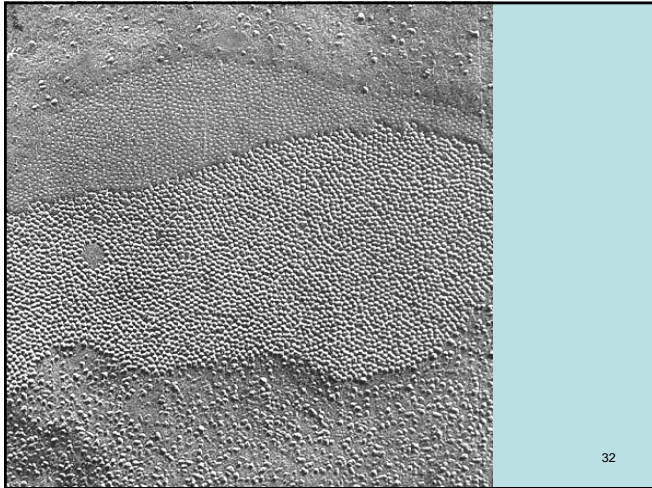
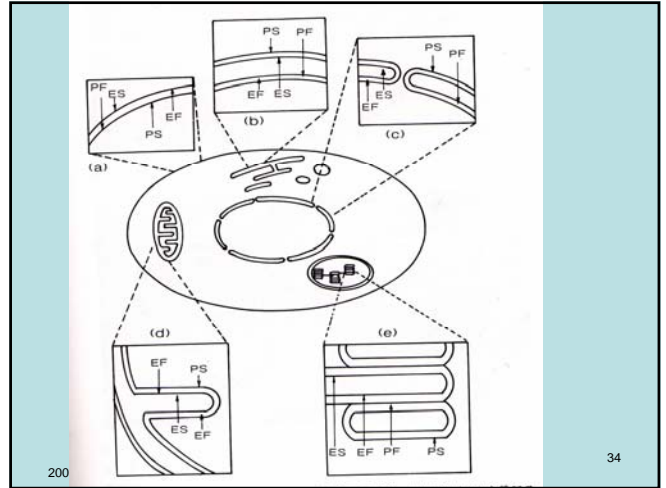
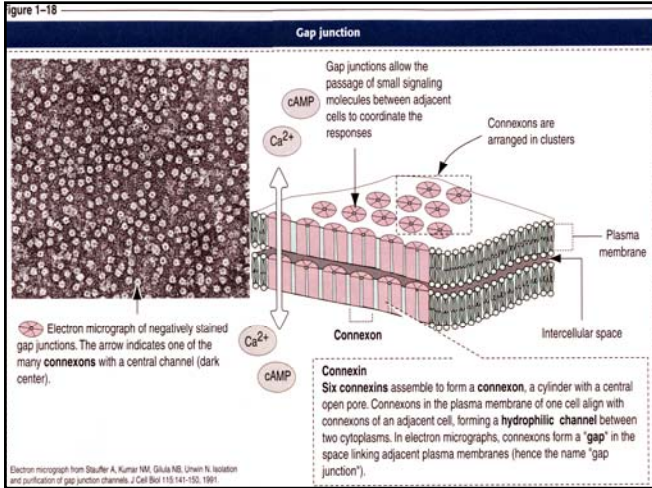


This diagram shows the freeze-fracture of the plasma membrane, revealing the outer leaflet (E face) and inner leaflet (P face) with extracellular fluid and cytoplasm frozen in place.

Freeze-fracture of PM*

* Final product of FF is visualized as SEM of P/E face platinum shadows.





Fracture Plane Is the Only Plane and Intramembranous:

A. Intramembranous particles (IMP), 8.5nm in diameter

B. The membrane fracture face:

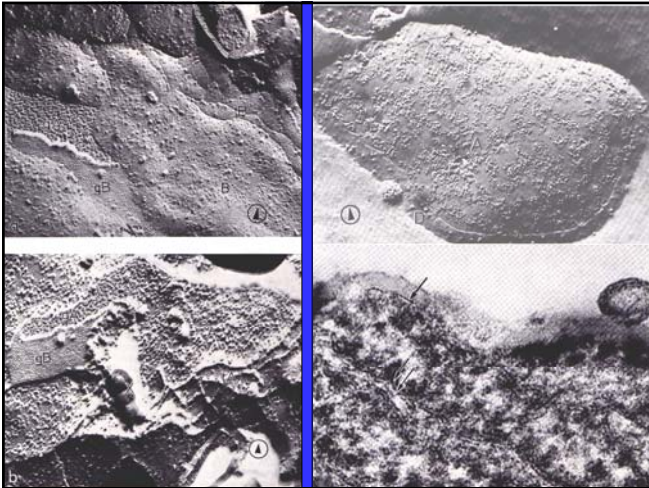
1. complementary replica
2. surface labelling - ferritin and *freeze-etching*
3. thin sections

C. Particles in membranes:

1. lack of E-face pit
2. the nature of the particles

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summary

- Guidelines of the course
- Resolution of microscope --
- EM basic principle – TEM (HVEM), SEM
- Freeze-fracture
 - Procedures,
 - P-face, E-face and P-surface and E-surface
 - Anchoring junctions,
 - Tight junction – strand and groove
 - Gap junction – connexons,
 - Fracture plane is unique and intramembranous

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